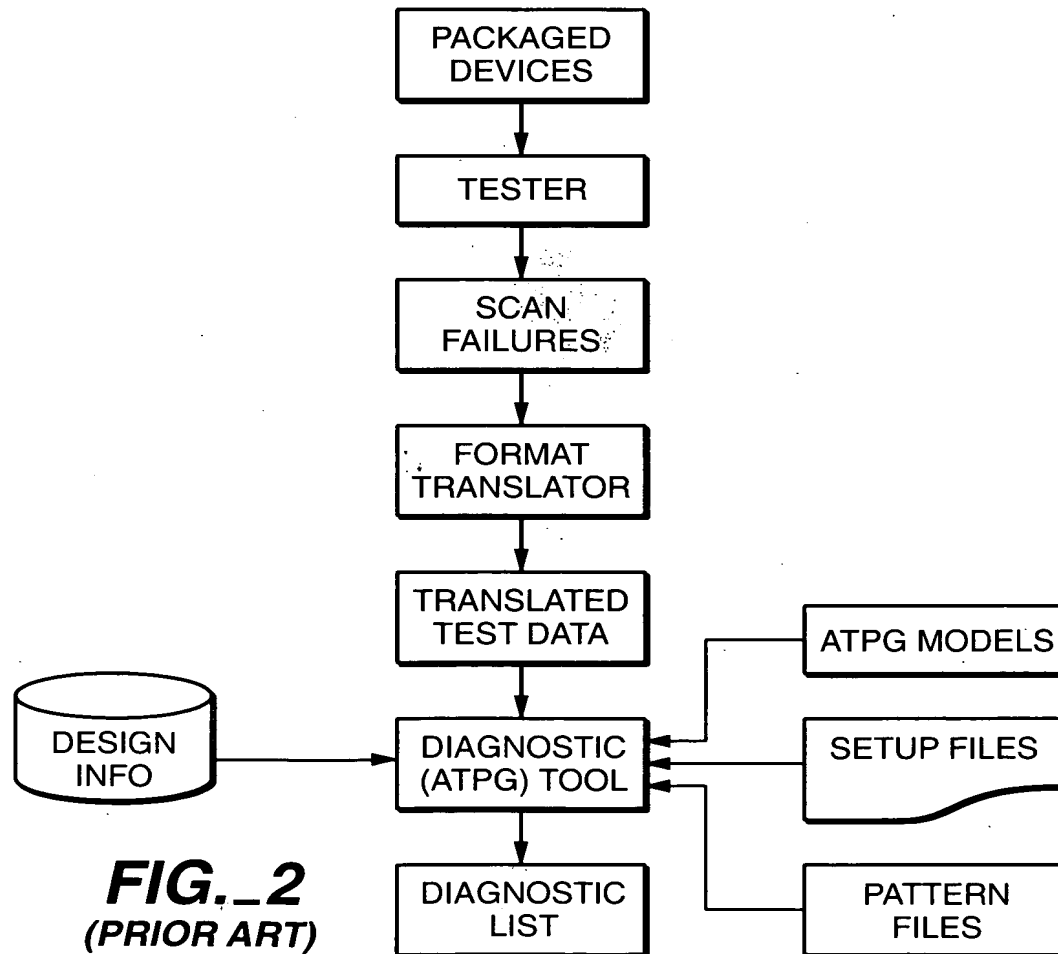
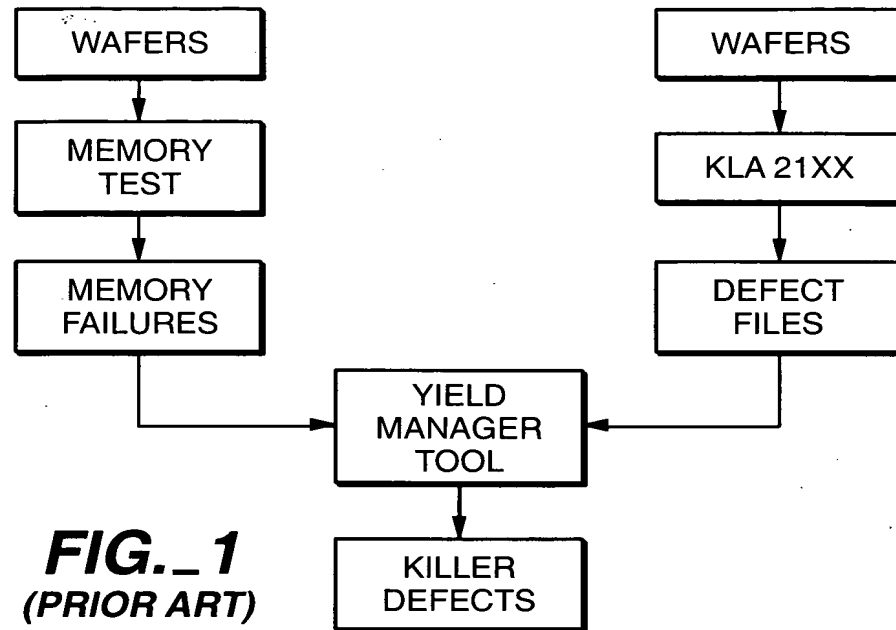


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APPROVED	Q.G. FIG.	
BY	CLASS	CLASS
DRAFTSMAN	714	724

2 / 9

```

DeviceID = DEMOID
LotID = TESTLOT01
WaferID = 01
DIE = -4,0
datalog.scan.10 diagnosis summary, #failing_patterns=9 #defects=2
#unexplained_fails=2
unexplained patterns = 212 250

```

```

-----
fault candidates for defect 1, #failing_patterns_explained=5
-----

```

Warning: Fault candidates will cause passing patterns to fail.
failing patterns explained = 322 706 738 770

```

type   code   pin_pathname
-----

```

```

1  DS   /XTIO_0/XTTLI8_1612/N2_23
1  DS   /PI9
-----

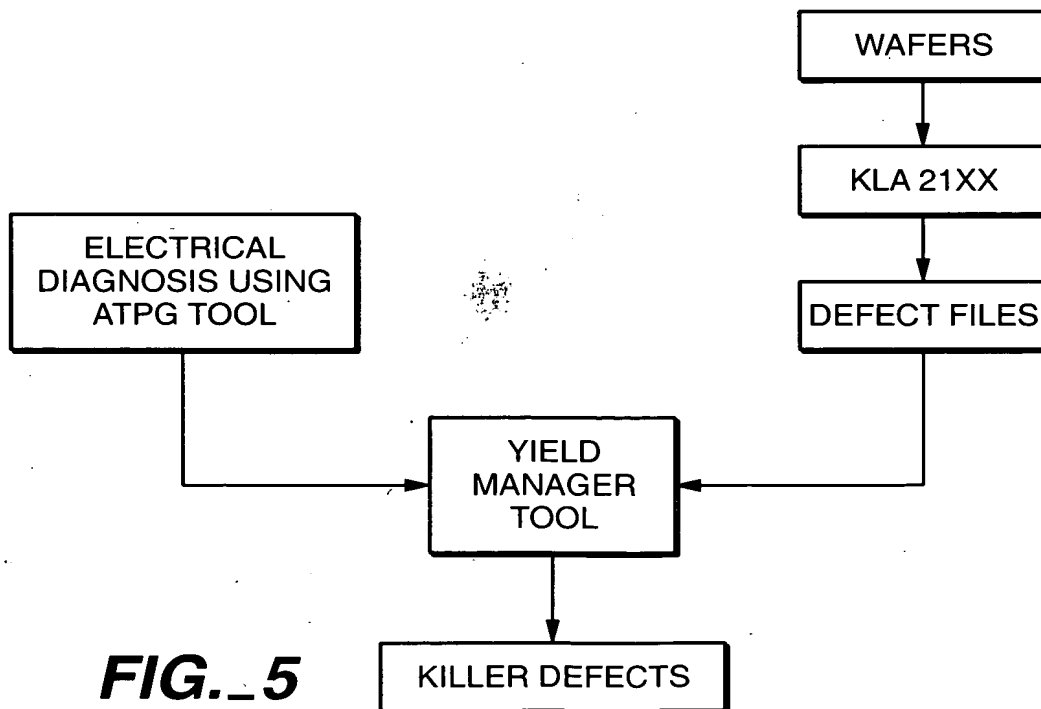
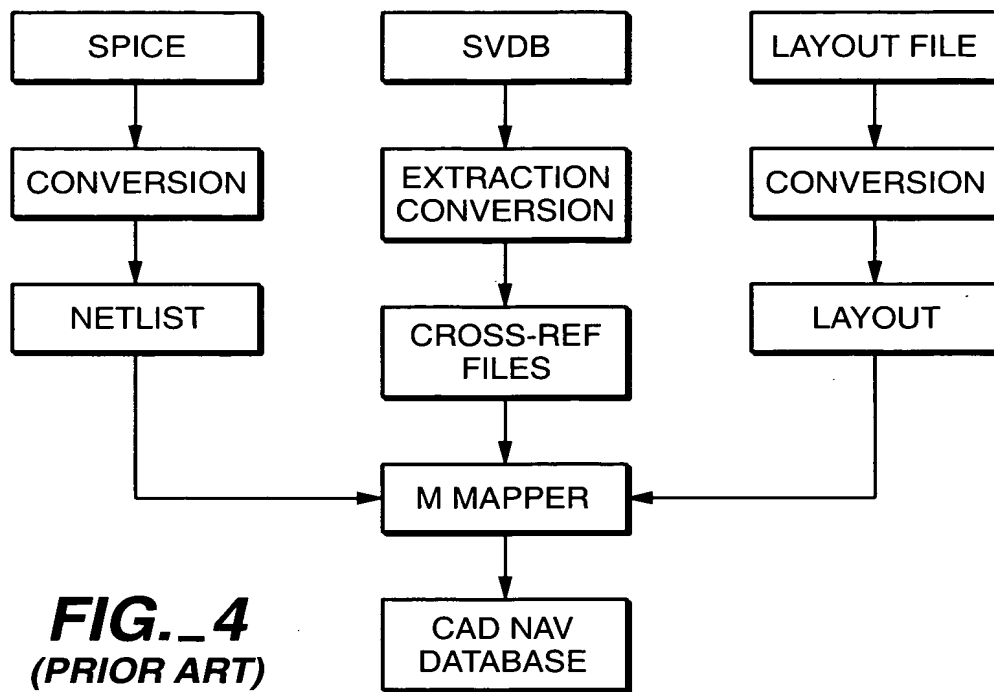
```

```

diagnosis CPU time = .68 sec

```

FIG.-3
(PRIOR ART)



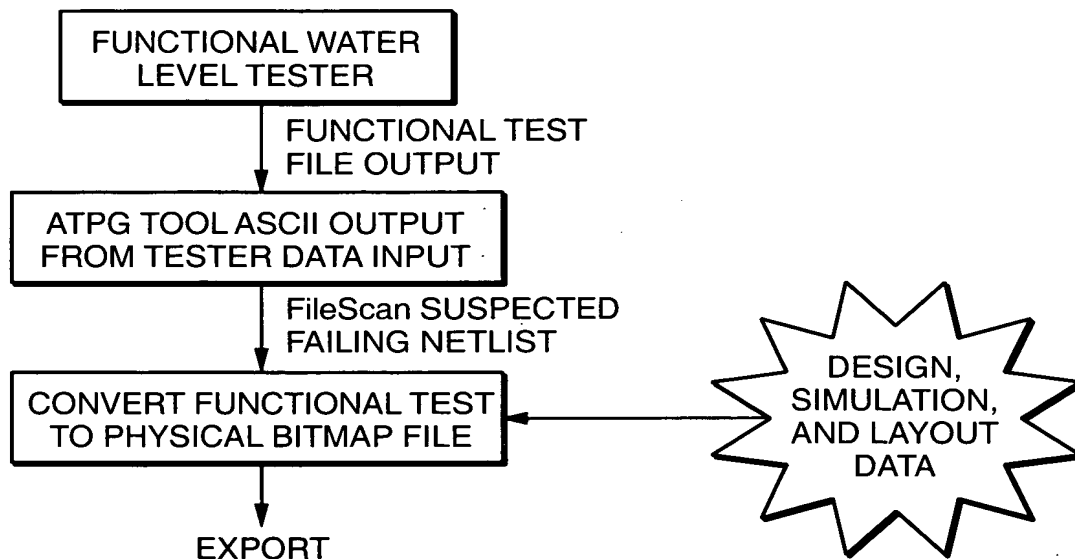
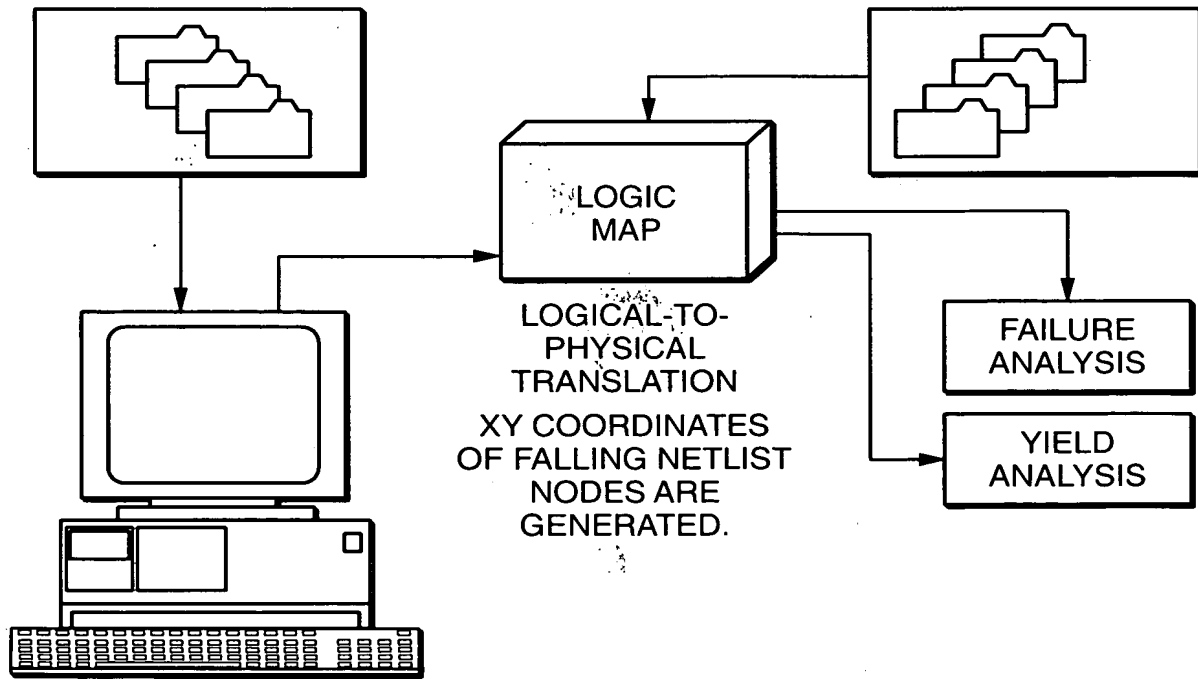


FIG._6

TESTER GENERATED FILES
TESTERS GENERATE
DATALOGS FOR EACH
DIE TESTED.

DESIGN DATA
LogicMap READS THE
GDSII FILE INPUT,
NETLIST AND LSV DATA.



FastScan UNIX SERVER
A FRACTION OF THE
DATALOGS ARE TRANSLATED
INTO FastScan FORMAT.

FIG._10

APPROVED	O.G. FIG.	
BY	CLASS	SUBCLASS
DRAFTSMAN	714	724

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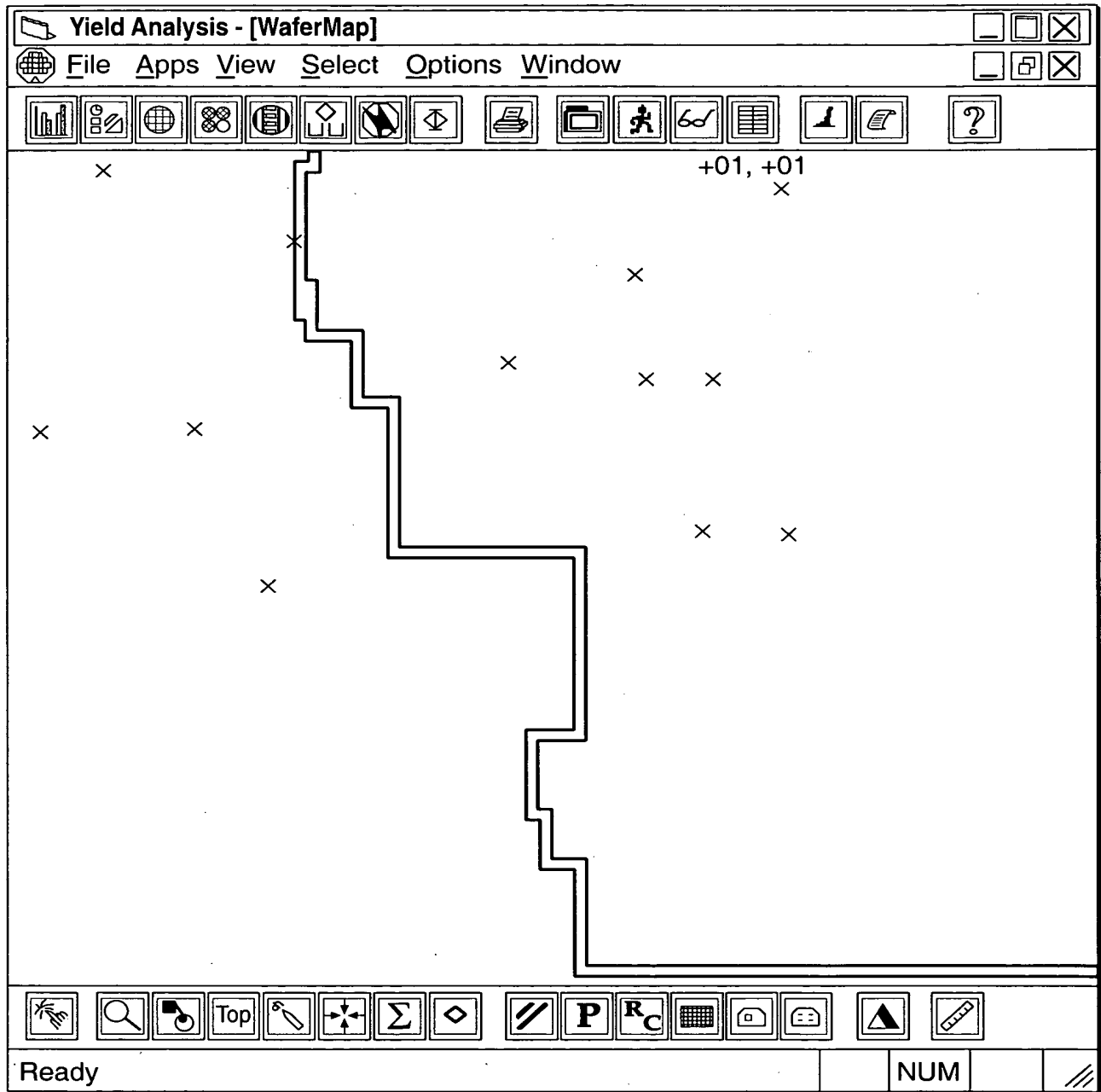


FIG._7

APPROVED	Q.G. FIG.	
BY	011829	CLASS
DRAFTSMAN	714	724

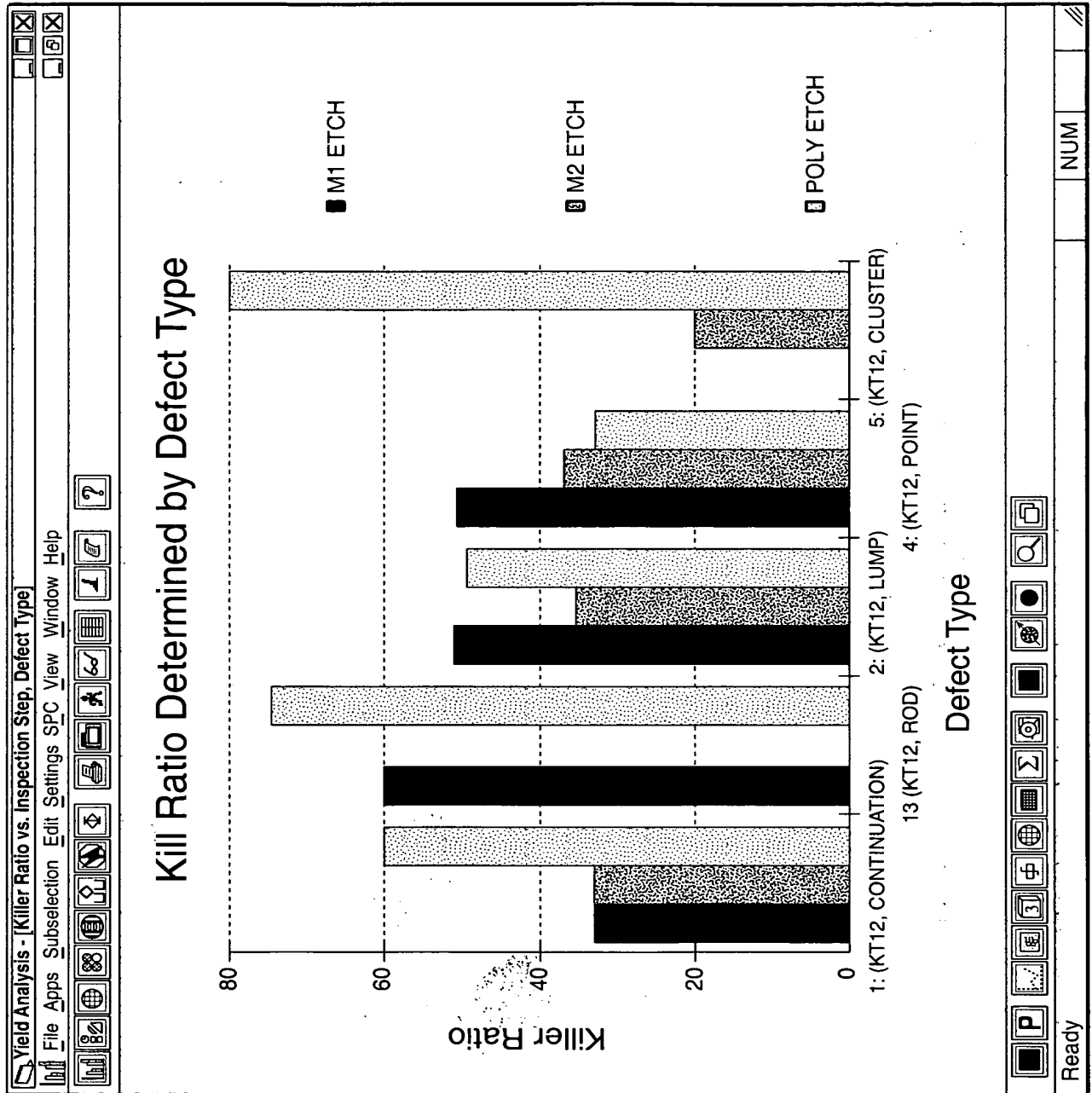


FIG.-8

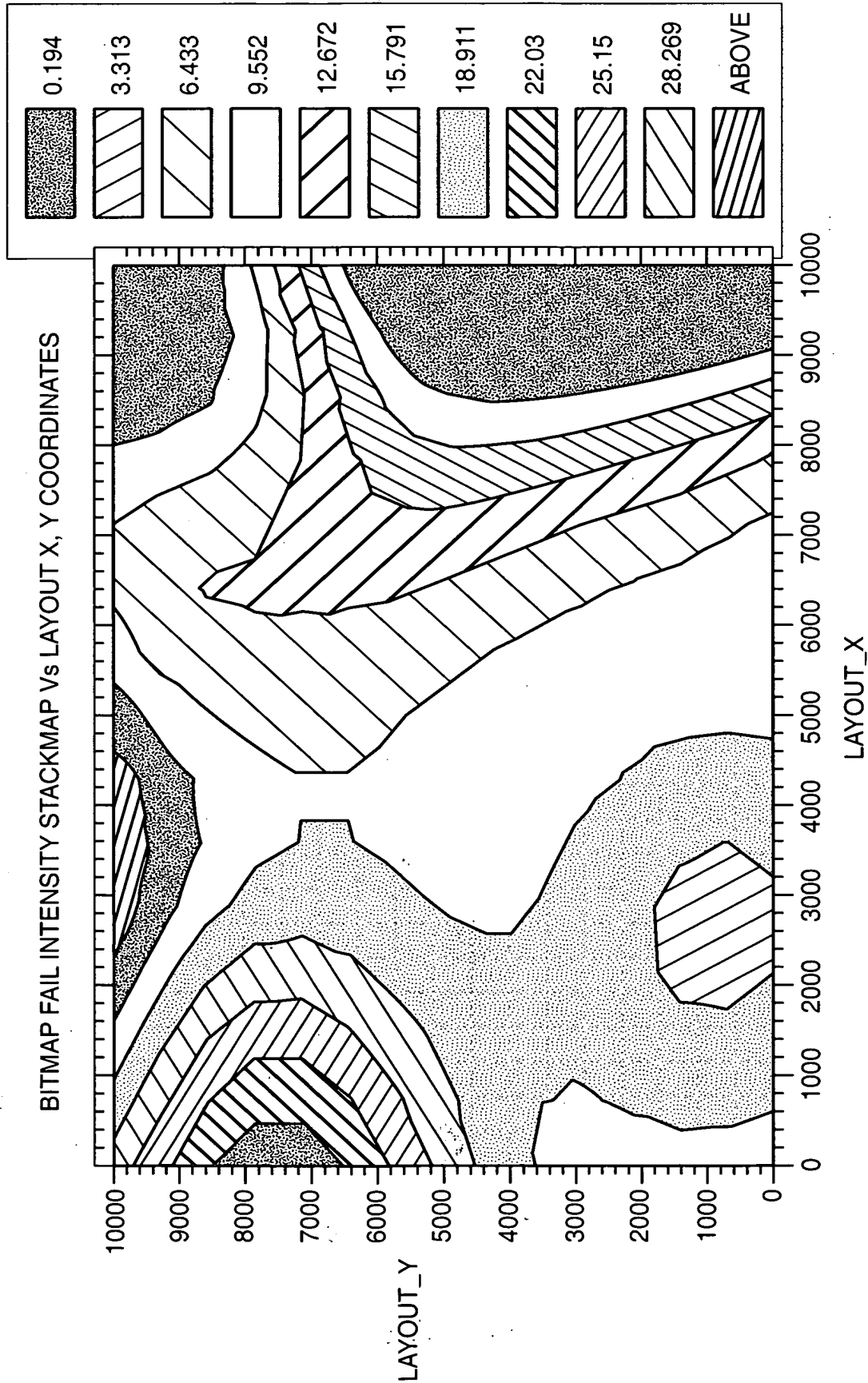


FIG..9

APPROVED	O.G. FIG.
BY 014826	CLASS
DRAFTSMAN	7/4 73

8 / 9

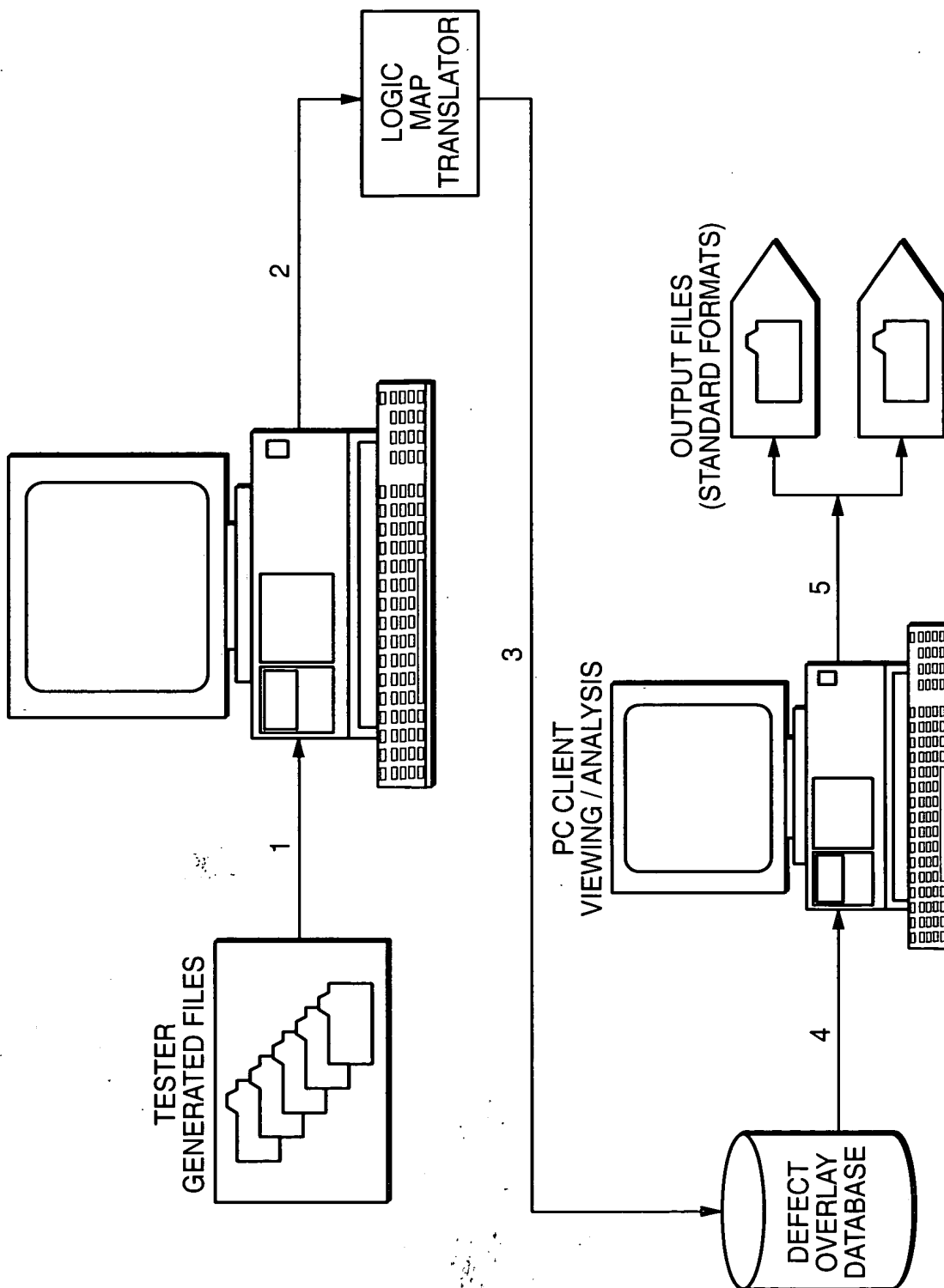


FIG..11

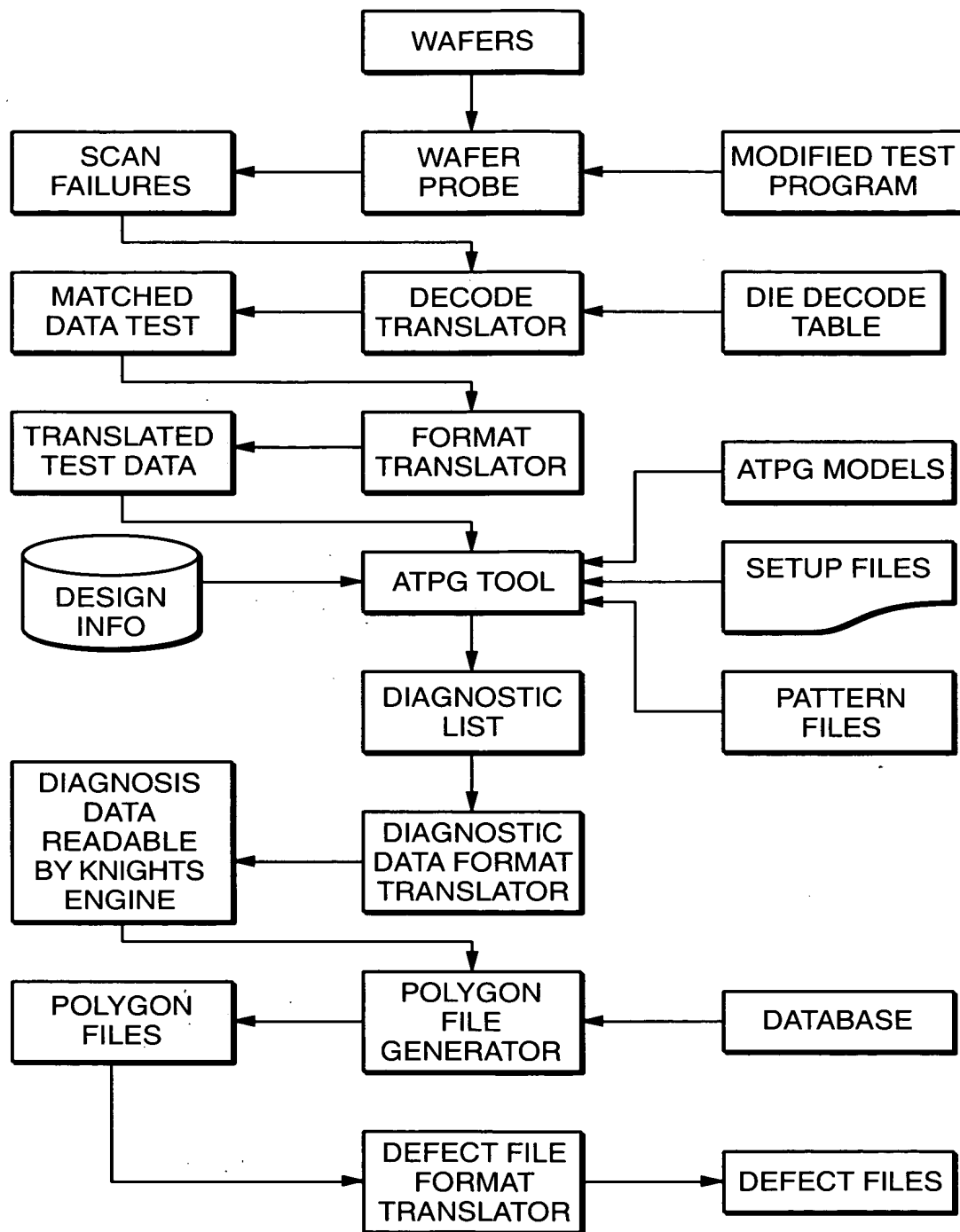


FIG. 12